

Electronic Instrumentation

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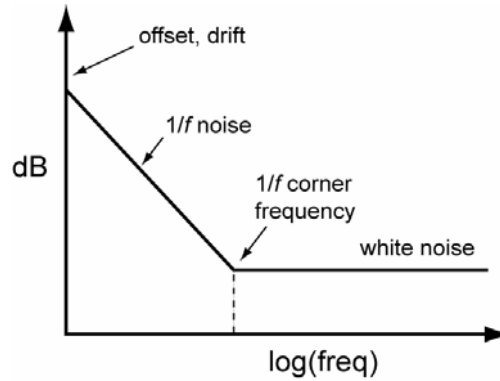
Introduction

- Synonyms: coherent detection, synchronous demodulation, lock-in amplification, chopping??
- These are all modulation techniques that are used to improve the low frequency performance of measurement systems
- When square-wave modulation is employed, the technique is referred to as chopping
- Chopping leads to improved low-frequency specs e.g. reduced offset and $1/f$ noise, better CMRR and PSRR

Characterized by

- Offset, gain error
- Drift, $1/f$ noise
- PSRR, CMRR

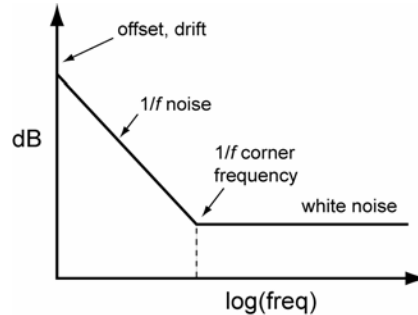
What can we do?



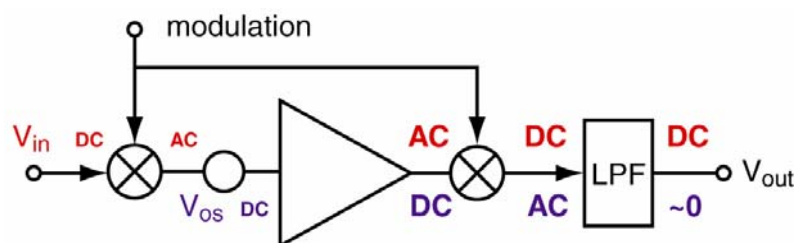
- Offset, gain error and $1/f$ noise are caused by component mismatch and non-idealities
⇒ they are a part of life!
- But we can reduce their effects by
 - Static techniques like calibration and trimming
 - Dynamic techniques such as chopping, auto-zeroing and dynamic element matching

- Involves measuring a static error of a system (e.g. offset or gain error) and then adjusting the value of a component in order to reduce the error to zero.
- + Low complexity
- + No bandwidth limitation
- Requires measurement equipment
- Also requires a memory element to store the trimmed value e.g. a potentiometer, or a PROM

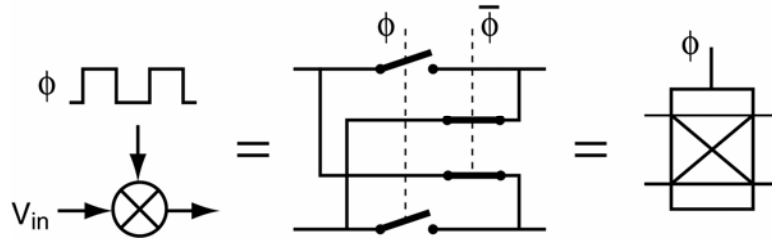
- Techniques that continuously attempt to cancel the effect of system non-idealities to zero.
- + (Usually) do not require measurement equipment
- + Also compensate for drift and $1/f$ noise and improve CMRR and PSRR
- Requires more complex circuitry
- Reduced bandwidth
- Two main Dynamic Offset Cancellation (DOC) techniques are: **Chopping** and **Auto-zeroing**



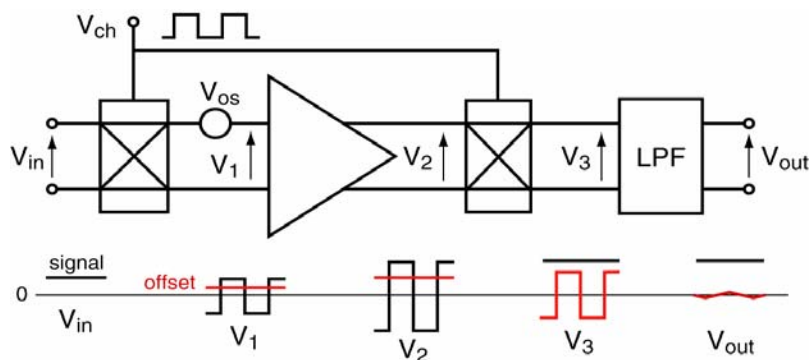
- Time domain \Rightarrow Auto-zeroing \Rightarrow periodically measure the offset (noise) and subtract it from the input signal
- Frequency domain \Rightarrow Chopping \Rightarrow modulating the input signal above the $1/f$ noise



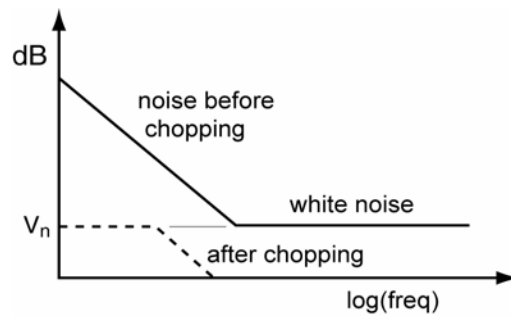
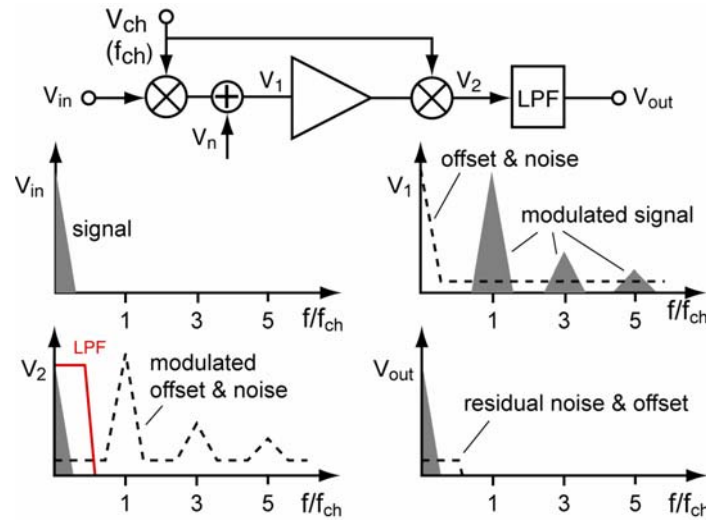
- Signal is modulated, amplified and then demodulated
- DC offset is modulated **once** and the resulting AC signal can be removed by a low-pass filter
- The modulators are usually implemented as polarity reversing switches, known as choppers
- The technique is known as “chopping”



- Easily generated modulating signal
- Modulator is a simple polarity-reversing switch
- Switches are easily realized in CMOS

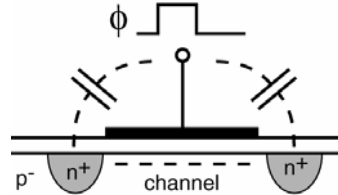


- Output chopper converts offset into a square-wave!
- To avoid residual offset, the duty-cycle of the square-wave should be exactly 50%
- Non-ideal LPF \Rightarrow residual ripple

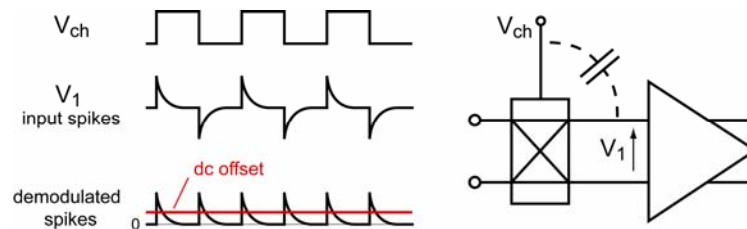


- **Complete** suppression of $1/f$ noise if $f_{ch} > 1/f$ corner freq. but harmonics \Rightarrow slightly $(\pi^2/8)$ more noise power
- But up-modulated offset must be filtered out \Rightarrow loss of signal BW and residual chopper "ripple"

C.C. Enz and G.C. Temes, "Circuit Techniques for Reducing the Effects of Op-Amp Imperfections: Autozeroing, Correlated Double Sampling, and Chopper Stabilization," Proceedings of the IEEE, 1996

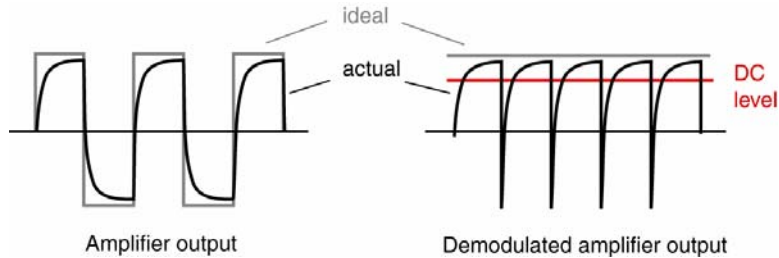


- Charge injection occurs when MOSFETs switch OFF
- Channel charge, $Q_{ch} = WLC_{ox}(V_{GS} - V_t)$
- Clock feed-through is caused by capacitive coupling via the overlap capacitance between gate and the source/drain diffusions



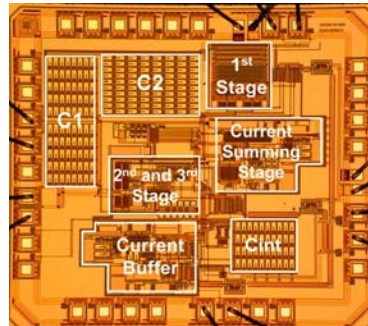
Main causes

- Clock asymmetry (non-50% duty-cycle)
- Clock feed-through and charge injection cause spikes at the amplifier's input
- These spikes are then demodulated back to DC by the output chopper \Rightarrow residual offset (microvolts)
- Residual offset is proportional to chopping frequency



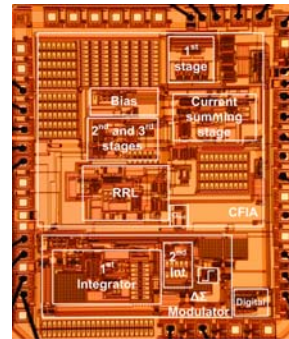
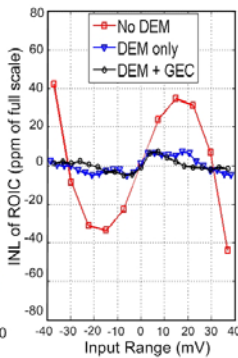
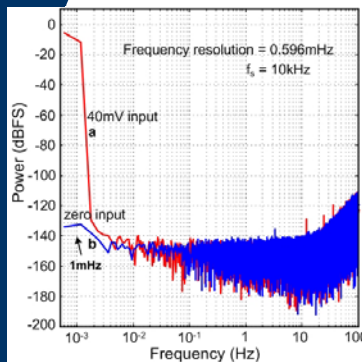
- Limited amplifier BW means that the output signal will not be a perfect square-wave \Rightarrow less gain
- In other words chopping reduces DC gain!

- Chopping is a powerful technique that can be used to reduce offset and $1/f$ noise in amplifiers and systems
- Main drawback is the need for a LPF to remove the up-modulated offset \Rightarrow bandwidth limitation
- Main non-idealities are caused by finite BW, clock asymmetry and chopper spikes
- Offsets as low as a few nV can be achieved!



- Three-stage amplifier, first two stages are chopped
- Achieved a 1mHz 1/f corner frequency, 5uV offset voltage, CMRR and PSRR > 120dB

R. Wu, K.A.A. Makinwa and J.H. Huijsing, "A Chopper Current-Feedback Instrumentation Amplifier with a 1mHz 1/f Noise Corner and an AC-Coupled Ripple Reduction Loop," *J. Solid-State Circuits*, vol. 44, is. 12, pp. 3232 – 3243, Dec. 2009.



- Precision IA and a 21-bit $\Sigma\Delta$ ADC (10Hz BW)
- 200nV offset, 0.04% gain error, 10ppm linearity

R. Wu, K.A.A. Makinwa and J.H. Huijsing, "A 21b $\pm 40\text{mV}$ Range Read-Out IC for Bridge Transducers," *J. Solid-State Circuits*, vol. 47, is. 9, pp. 2152 – 2163, Sept 2012..

- A thermistor is read out by incorporating it into a $\frac{1}{4}$ Wheatstone bridge with three other temperature-stable resistors whose value is equal to the thermistor's nominal value at room temperature
- The bridge and the amplifier are driven from a temperature-stable 5V supply
- The thermistor has a nominal value of $65\text{k}\Omega$ at 25°C , and a temperature coefficient $S = 0.04\%/^\circ\text{C}$
- The bridge is read out by an differential amplifier whose thermal noise is at the same level as that of the bridge. The amplifier also suffers from $1/f$ noise, with a corner frequency of 5kHz .
- The amplifier is followed by a 1st order low-pass filter with a 100Hz cut-off frequency

- a) To deal with its $1/f$ noise and offset, the amplifier is chopped. If the noise at the output of the system is to be minimized, what is the lowest possible chopping frequency?
- b) Assuming that the amplifier has an initial offset of 5mV , estimate the amplitude (input-referred) of the chopper ripple present at the output of the system.
- c) Calculate the detection limit (in degrees Celsius) due to the thermal noise of the bridge and the amplifier.
- d) If the differential amplifier has a finite CMRR and PSRR and the power supply can vary by $\pm 10\%$, what CMRR and PSRR are required to ensure that the corresponding detection limit is less than 1mK ?

- Techniques that continuously attempt to cancel the effect of system non-idealities to zero.

- + (Usually) do not require measurement equipment
- + Also compensate for drift and $1/f$ noise and improve CMRR and PSRR
 - Requires more complex circuitry
 - Reduced bandwidth

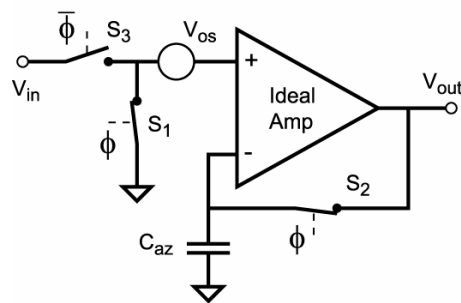
- Two main Dynamic Offset Cancellation (DOC) techniques are: **Chopping** and **Auto-zeroing**

Two basic methods

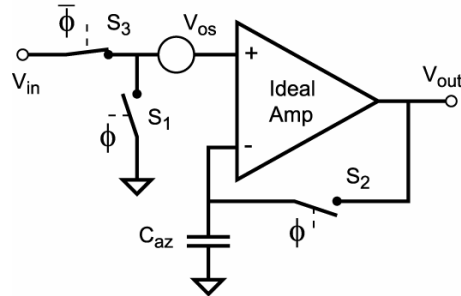
1. Modulate the offset away from DC and then remove it with a low-pass filter it out \Rightarrow Chopping

2. Store the offset in a memory element and then subtract it from the input signal \Rightarrow Auto-zeroing

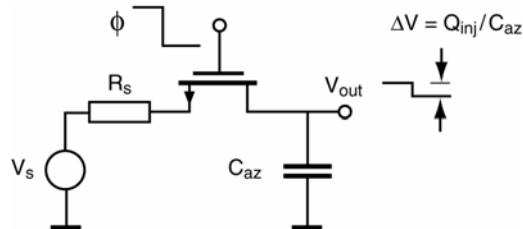
- Basic idea is to remove the signal, measure and store the offset and subsequently subtract the stored offset from the input signal
- This means that the amplifier is not continuously available => bandwidth limitation
- A memory element is needed to store the offset



- $S_{1,2}$ closed $\Rightarrow V_{out} = V_{os}$
- So the amplifier's offset is stored on C_{az}

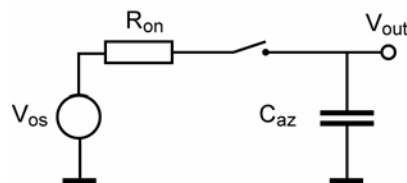
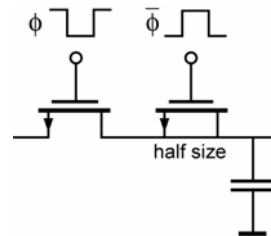
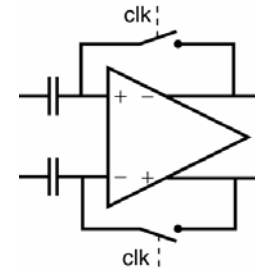


- S_3 closed \Rightarrow output signal is available
- For an amplifier with *finite* DC gain A , the residual offset is given by $V_{os}/(A+1)$



- Clock feed-through and charge injection \Rightarrow errors in stored offset
- Stored offset on C_{az} will slowly leak away
- In practice C_{az} is made as large as possible

- Use minimum size switches (subject to noise & speed requirements)
- Use differential topologies \Rightarrow 1st order cancellation
- For single-ended topologies dummy switches help [5,6]
- **But** main switch area will be $\sim 2x$ minimum size \Rightarrow more CI \Rightarrow limited benefit

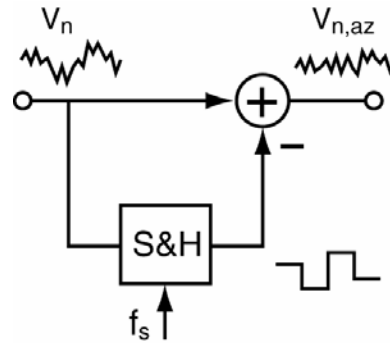


- Thermal noise of R_{on} is filtered by C_{az} (kT/C noise)
- Instantaneous value of the noise is “frozen” every time the switch opens \Rightarrow noise is exacerbated
- Accurate sampling of V_{os} \Rightarrow large C

Residual Noise of Auto-Zeroing (1)

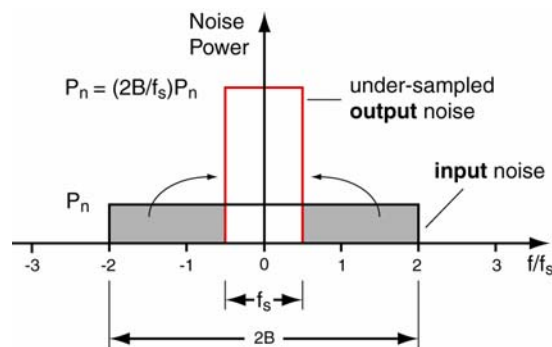
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- $V_{n,az}(f) = V_n(f) * (1 - H(f))$
- $H(f)$ is the frequency response of the S&H
- $H(f) = \text{sinc}(f)$
 $\Rightarrow 1-H(f)$ is a HPF
 \Rightarrow Offset and $1/f$ noise reduction!



Residual Noise of Auto-Zeroing (2)

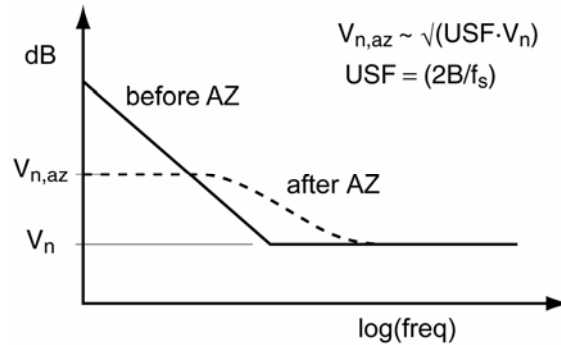
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- Since $B > f_s$ (settling!) \Rightarrow white noise is aliased
- Folded white noise is LP filtered by S&H i.e. by $H(f)$
- Baseband ($1/f$) noise is HP filtered i.e. by $1-H(f)$

Residual Noise of Auto-Zeroing (3)

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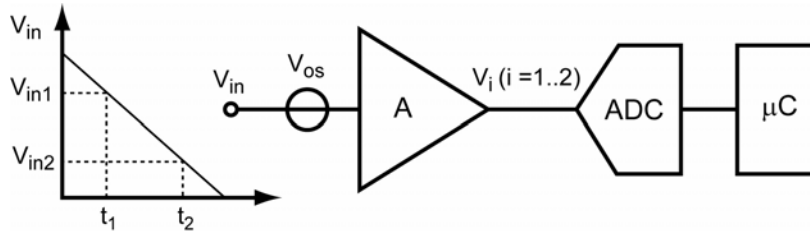


- $1/f$ noise is removed **but** noise foldover occurs
- For a 1st order LPF, noise bandwidth = $\pi f_c/2$

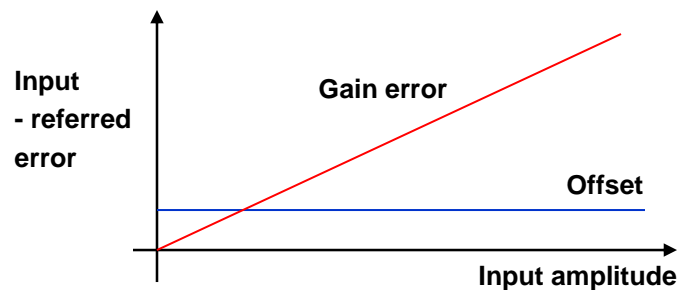
Auto-zeroing: Summary

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- Auto-zeroing is a powerful offset and $1/f$ noise reduction technique for amplifiers and systems
- Unlike chopping it does not suffer from ripple, but its noise performance is worse due to aliasing
- Main non-idealities are caused by switching spikes, leakage currents and (sometimes) by finite gain
- Offsets of a few microvolts can be reached



- Sometimes only a signal **difference** is of interest
 - Phase 1: $V_1 = A(V_{in1} + V_{os})$
 - Phase 2: $V_2 = A(V_{in2} + V_{os})$
 - $\Rightarrow (V_1 - V_2) = A(V_{in1} - V_{in2})$
- To maximize suppression of $1/f$ noise, the interval $t_1 - t_2$, should be as short as possible



- For small signals, offset dominates, while for large signals, gain error dominates
- Gain error, like offset, is a static error, which can be removed by calibration and/or trimming
- It can also be removed by dynamic element matching

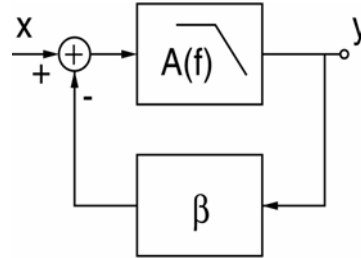
If $A(f) \cdot \beta \gg 1 \Rightarrow A_{CL} \cong 1/\beta$.

For moderate $1/\beta$, op-amp
DC gain is large enough!

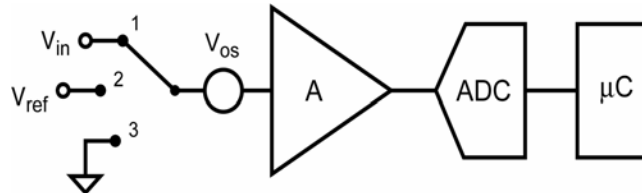
$\beta \Rightarrow$ Resistor/Capacitor ratios.
Resistors \Rightarrow 0.01%, 5 ppm/°C
Capacitors \Rightarrow 1%, 500 ppm/°C

$\Rightarrow A_{CL}$ can be accurately defined

But can we do better?



$$A_{CL} = \frac{x}{y} = \frac{A}{(1+A\beta)}$$

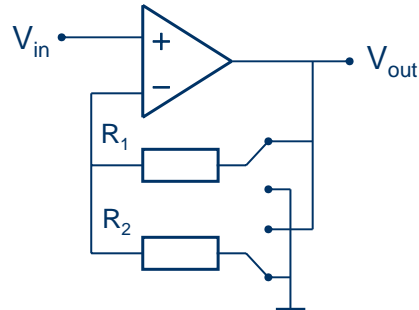


- Measurement requires 3 phases

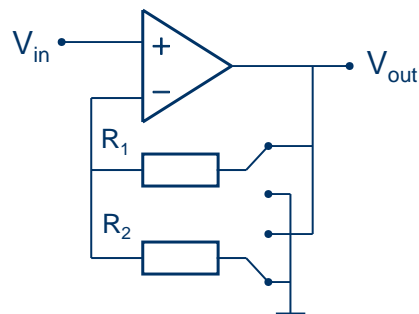
- Phase 1: $V_1 = A(V_{os} + V_{in})$
- Phase 2: $V_2 = A(V_{os} + V_{ref})$
- Phase 3: $V_3 = AV_{os}$

$\Rightarrow A, V_{os}$ and V_{in} can be found

- Accuracy is limited by ADC resolution and noise



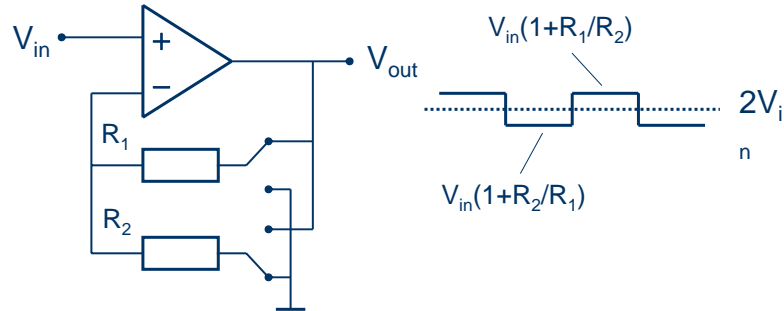
- Gain error can be further reduced by using Dynamic Element Matching (DEM)
- DEM involves swapping the **position** of nominally identical elements in a circuit
- This significantly reduces the average error



- Gain of 2 \Rightarrow 2 identical resistors i.e. $R_1=R_2$
- DEM can be applied by using switches to swap the position of mismatched resistors in the circuit
- Accuracy is limited by mismatch of switch resistance

Accurate x2 Amplifier with DEM (2)

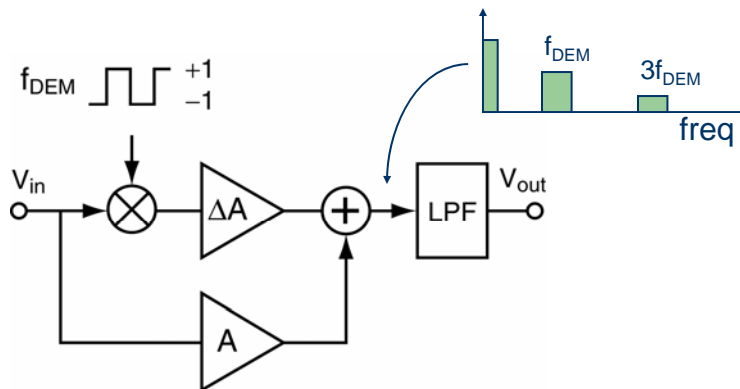
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- Average value of $V_{out} \sim 2V_{in}$
- V_{out} contains AC components which must be removed by a LPF (like chopping)
- So chopping and DEM can be easily combined

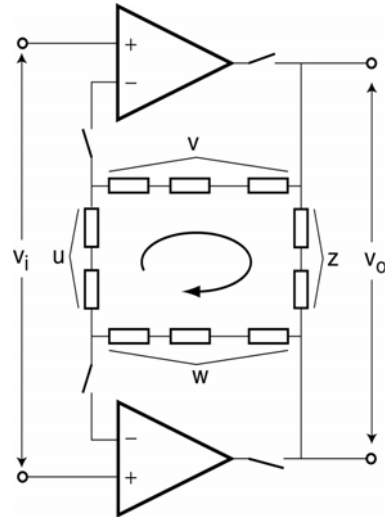
DEM in the Frequency Domain

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- Mismatch is shifted to harmonics of f_{DEM}
- To avoid unwanted intermodulation, $f_{in} < f_{DEM}/2$

- Feedback via a chain of matched resistors.
- Chain is rotated by a bank of switches and the gain, A is averaged.
- $A = 1 + (v+w)/u$
- NB: Switch resistance has no effect, why?



PRO

- Gain (ratio) error can be reduced to ppm levels

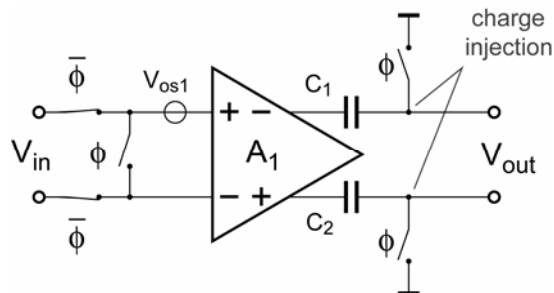
CONS

- Switches are required to swap components
⇒ extra circuit complexity, switching transients
- Result must be averaged ⇒ BW reduction
- Input signal must be band-limited ($f_{in} < f_{DEM}/2$) to prevent inter-modulation products

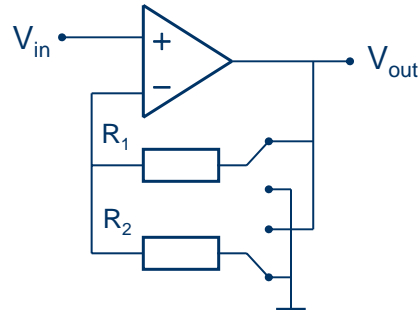
- Precise gain can be achieved by feedback
 - discrete resistors \Rightarrow 0.01%
 - on-chip \Rightarrow 0.1% due to mismatch

- Better performance can be achieved by using DEM, but like chopping, this is at the expense of BW

- If the signal is digitized, the 3-signal method is also effective, but accuracy is limited by ADC resolution



- a) The amplifier shown above has 10mV offset and a gain of 1000. Each switch is associated with 100pC of charge injection. Assuming that their mismatch is less than 10%, how big must the capacitors be to achieve 20 μ V offset after auto-zeroing.



- b) If the $R_1 \sim R_2$ and their mismatch is 1%, calculate the residual gain error after DEM
- c) What is the residual gain error if the DEM control signal is asymmetric: with a 49% duty-cycle
- d) What is the effect of finite switch resistance?

- e) A measurement system employs the 3-signal method. If it makes use of a 5V reference, how many bits of resolution must its ADC have in order to achieve a residual offset of less than $20\mu\text{V}$.